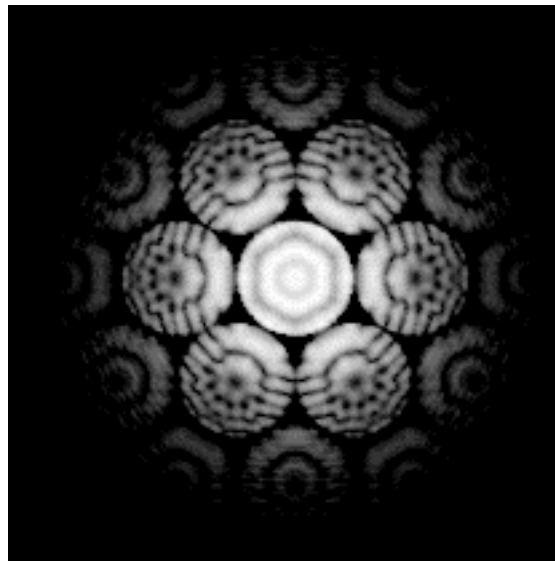


*Optional
Function*

CBED

for *MacHREM*TM / *WinHREM*TM

Coherent Convergent Beam Electron Diffraction Pattern Simulation Program



Simulated CBED pattern for Si [111]

This optional function adds the capability for simulating coherent convergent beam electron diffraction (CBED) patterns to the *MacHREM*TM / *WinHREM*TM program suite.

- **User Friendly Graphical Interface** Even a novice user can easily generate his/her data and perform computation.
- **Reliable and Efficient Algorithm** Dynamical electron interaction is efficiently estimated by using the FFT multislice technique.
- **High Quality Image Output** All images are generated with a standard image format of Windows/Mac OS. Therefore, high quality images can be printed from them, and they can be imported into another application.

Please Contact to:

HREM Research Inc.

14-48 Matsukazedai, Higashimatsuyama, 355-0055 JAPAN

TEL/FAX (81) 493-35-3919

email: support@hremresearch.com